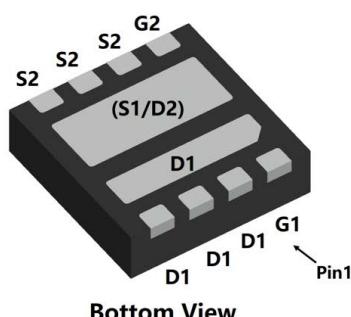
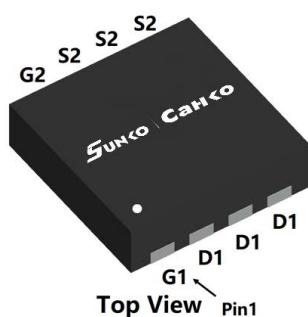
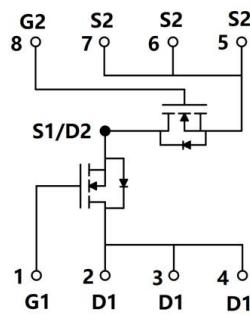


N-Channel and N-Channel Complementary MOSFET



DFN3030-8L



Product Summary

NMOS(Die1)

- V_{DS} 30V
- I_D 30A
- $R_{DS(ON)}$ (at $V_{GS}=10V$) $<10m\Omega$
- $R_{DS(ON)}$ (at $V_{GS}=4.5V$) $<19.5m\Omega$

NMOS(Die2)

- V_{DS} 30V
- I_D 40A
- $R_{DS(ON)}$ (at $V_{GS}=10V$) $<6.5m\Omega$
- $R_{DS(ON)}$ (at $V_{GS}=4.5V$) $<15m\Omega$

General Description

- Dual Asymmetric N-Channel
- High Current Capability
- Low Gate Charge
- Epoxy Meets UL 94 V-0 Flammability Rating
- Halogen Free

Applications

- DC/DC Converters in Computing, Servers
- Isolated DC/DC Converters in Telecom and Industrial

Absolute Maximum Ratings ($T_A=25^\circ C$ unless otherwise noted)

Parameter		Symbol	NMOS(Die1)	NMOS(Die2)	Unit
Drain-source Voltage		V_{DS}	30	30	V
Gate-source Voltage		V_{GS}	± 20	± 20	V
Drain Current	$T_A=25^\circ C$	I_D	9	11	A
	$T_A=100^\circ C$		5	7	
	$T_C=25^\circ C$		30	40	
	$T_C=100^\circ C$		19	25	
Pulsed Drain Current ^A		I_{DM}	120	160	A
Avalanche energy ^B		EAS	42.2	60	mJ
Total Power Dissipation ^C	$T_A=25^\circ C$	P_D	1.56	1.66	W
	$T_A=100^\circ C$		0.62	0.66	
	$T_C=25^\circ C$		17.3	20.8	
	$T_C=100^\circ C$		6.9	8.3	
Junction and Storage Temperature Range		T_J, T_{STG}	-55~+150	-55~+150	°C

Thermal resistance

Parameter		Symbol	NMOS(Die1)		NMOS(Die2)		Units
			Typ	Max	Typ	Max	
Thermal Resistance Junction-to-Ambient ^D	Steady-State	$R_{\theta JA}$	67	80	62	75	°C/W
Thermal Resistance Junction-to-Case	Steady-State		6	7.2	5	6	

Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
SCQD3622A	F1	QD3622A	3000	30000	120000	13" reel

■ NMOS(Die1) Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Parameter						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	30	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
		$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}, T_J=150^\circ\text{C}$	-	-	100	
Gate-Body Leakage Current	I_{GSS}	$V_{\text{GS}}= \pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1.1	1.5	2.2	V
Static Drain-Source On-Resistance	$R_{\text{DS(on)}}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=13\text{A}$	-	7.5	10	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_{\text{D}}=10\text{A}$	-	14	19.5	
Diode Forward Voltage	V_{SD}	$I_{\text{S}}=10\text{A}, V_{\text{GS}}=0\text{V}$	-	-	1.2	V
Gate resistance	R_{G}	f=1MHz	-	3	-	Ω
Maximum Body-Diode Continuous Current	I_{S}		-	-	30	A
Dynamic Parameters						
Input Capacitance	C_{iss}	$V_{\text{DS}}=15\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	1020	-	pF
Output Capacitance	C_{oss}		-	140	-	
Reverse Transfer Capacitance	C_{rss}		-	125	-	
Switching Parameters						
Total Gate Charge	Q_{g}	$V_{\text{GS}}=10\text{V}, V_{\text{DS}}=15\text{V}, I_{\text{D}}=13\text{A}$	-	20.7	-	nC
Gate-Source Charge	Q_{gs}		-	3.8	-	
Gate-Drain Charge	Q_{gd}		-	5.3	-	
Reverse Recovery Charge	Q_{rr}	$I_{\text{f}}=13\text{A}, \text{di/dt}=100\text{A/us}$	-	161	-	nC
Reverse Recovery Time	t_{rr}		-	136	-	ns
Turn-on Delay Time	$t_{\text{D(on)}}$	$V_{\text{GS}}=10\text{V}, V_{\text{DD}}=15\text{V}, I_{\text{D}}=13\text{A}$ $R_{\text{GEN}}=2.2\Omega$	-	8.2	-	ns
Turn-on Rise Time	t_{r}		-	53.9	-	
Turn-off Delay Time	$t_{\text{D(off)}}$		-	18.4	-	
Turn-off fall Time	t_{f}		-	2.9	-	

■ NMOS(Die2) Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Parameter						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	30	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
		$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}, T_J=150^\circ\text{C}$	-	-	100	
Gate-Body Leakage Current	I_{GSS}	$V_{\text{GS}}= \pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1.1	1.5	2.2	V
Static Drain-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=15\text{A}$	-	5	6.5	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_{\text{D}}=10\text{A}$	-	11	15	
Diode Forward Voltage	V_{SD}	$I_{\text{S}}=10\text{A}, V_{\text{GS}}=0\text{V}$	-	-	1.2	V
Gate resistance	R_{G}	$f=1\text{MHz}$	-	3	-	Ω
Maximum Body-Diode Continuous Current	I_{S}		-	-	40	A
Dynamic Parameters						
Input Capacitance	C_{iss}	$V_{\text{DS}}=15\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	1320	-	pF
Output Capacitance	C_{oss}		-	185	-	
Reverse Transfer Capacitance	C_{rss}		-	170	-	
Switching Parameters						
Total Gate Charge	Q_{g}	$V_{\text{GS}}=10\text{V}, V_{\text{DS}}=15\text{V}, I_{\text{D}}=15\text{A}$	-	27	-	nC
Gate-Source Charge	Q_{gs}		-	5	-	
Gate-Drain Charge	Q_{gd}		-	7	-	
Reverse Recovery Charge	Q_{rr}	$I_{\text{F}}=15\text{A}, \text{di}/\text{dt}=100\text{A/us}$	-	157	-	nC
Reverse Recovery Time	t_{rr}		-	130	-	ns
Turn-on Delay Time	$t_{\text{D}(\text{on})}$	$V_{\text{GS}}=10\text{V}, V_{\text{DD}}=15\text{V}, I_{\text{D}}=15\text{A}$ $R_{\text{GEN}}=2.2\Omega$	-	10.8	-	ns
Turn-on Rise Time	t_{r}		-	64.8	-	
Turn-off Delay Time	$t_{\text{D}(\text{off})}$		-	22.5	-	
Turn-off fall Time	t_{f}		-	3.7	-	

- A. Repetitive rating; pulse width limited by max. junction temperature.
- B. NMOS(Die1): $T_J=25^\circ\text{C}, V_G=10\text{V}, R_G=25\Omega, L=0.5\text{mH}, IAS=13\text{A}$.
NMOS(Die2): $T_J=25^\circ\text{C}, V_G=10\text{V}, R_G=25\Omega, L=0.5\text{mH}, IAS=15.5\text{A}$.
- C. P_d is based on max. junction temperature, using junction-case and junction-ambient thermal resistance.
- D. The value of $R_{\theta JA}$ is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in the still air environment with $T_A=25^\circ\text{C}$.
The maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.

■ NMOS(Die1) Typical Electrical and Thermal Characteristics Diagrams

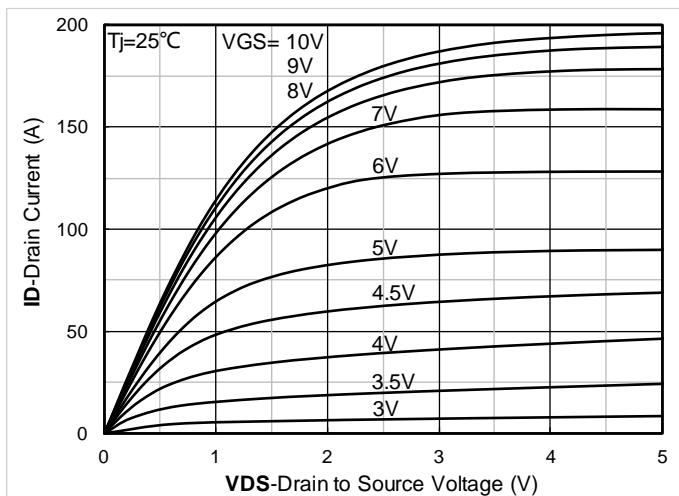


Figure 1. Output Characteristics

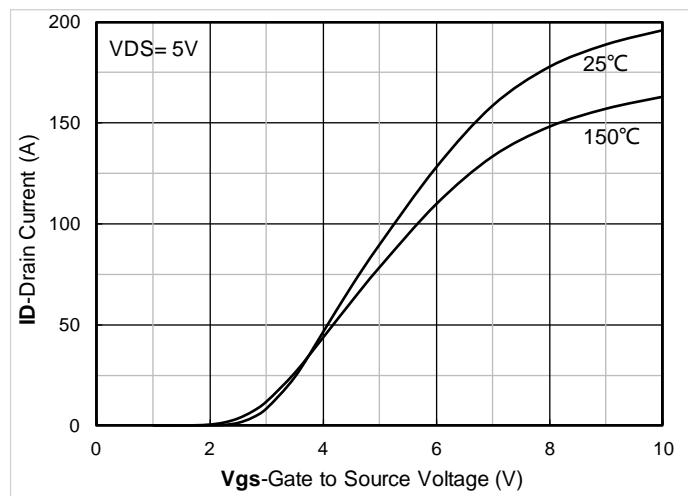


Figure 2. Transfer Characteristics

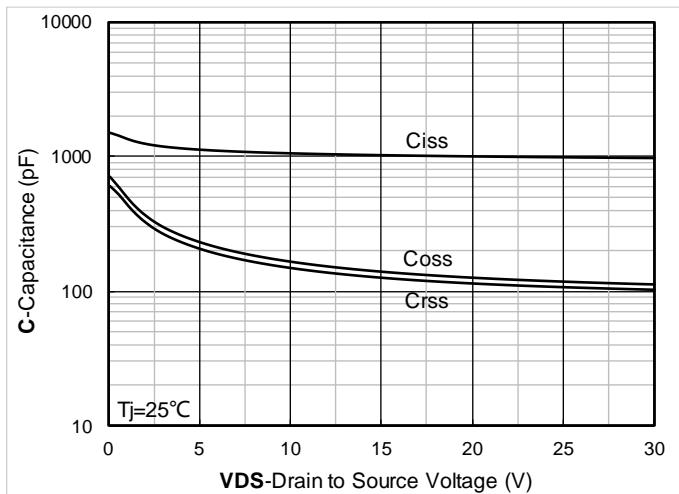


Figure 3. Capacitance Characteristics

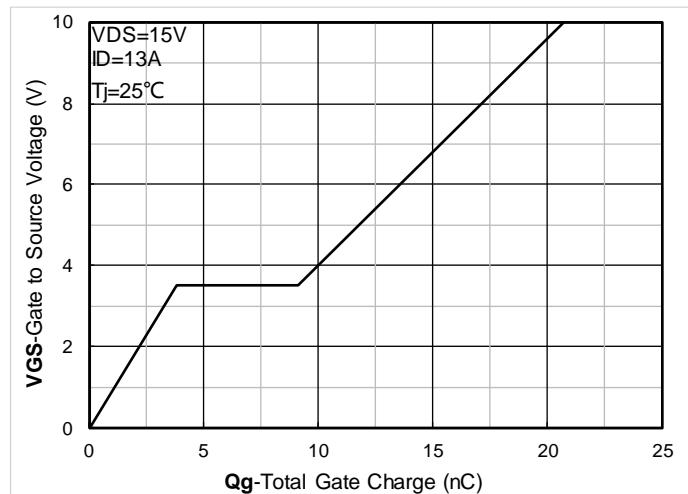


Figure 4. Gate Charge

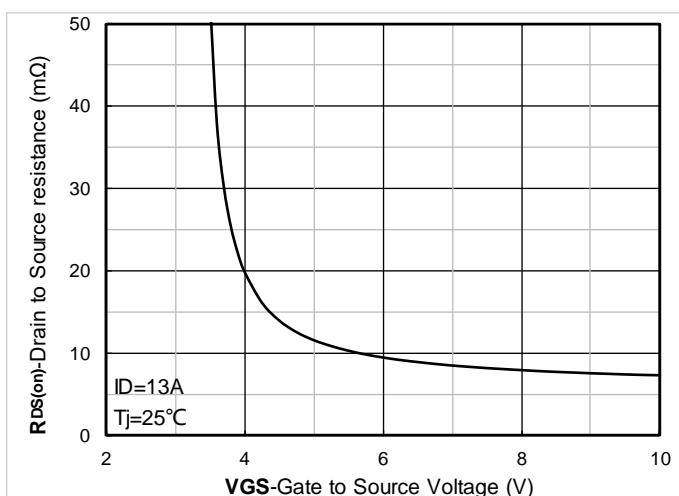


Figure 5. On-Resistance vs Gate to Source Voltage

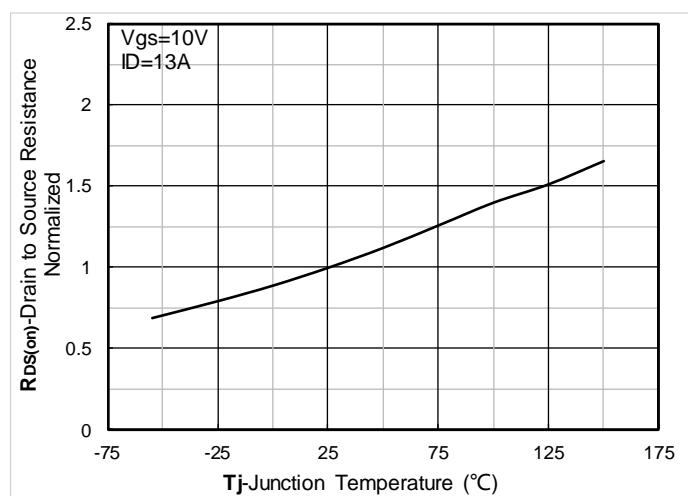


Figure 6. Normalized On-Resistance

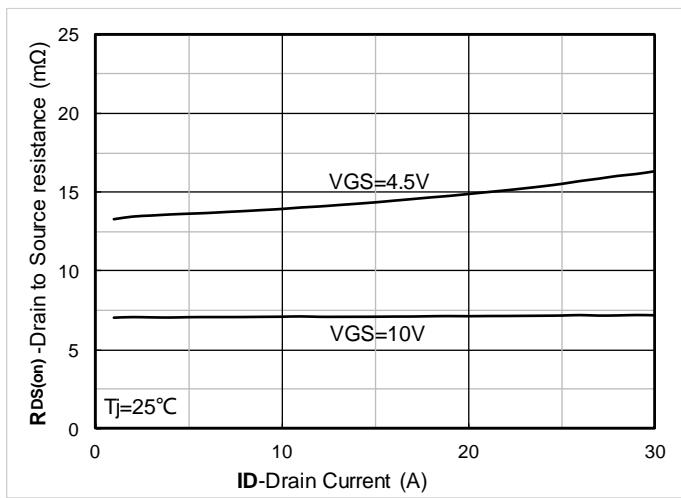


Figure 7. RDS(on) VS Drain Current

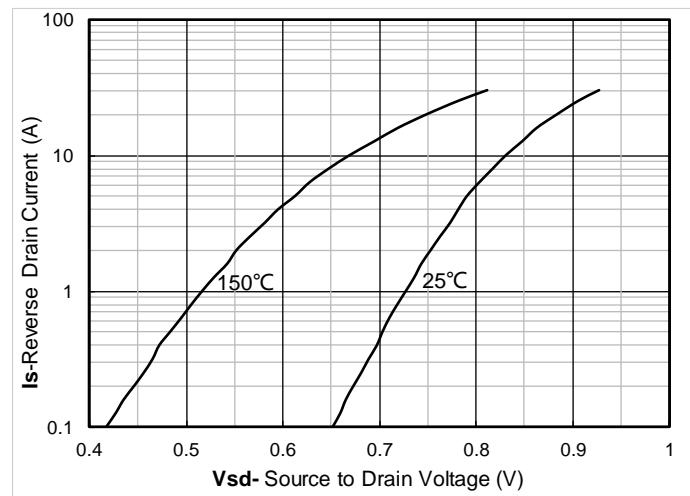


Figure 8. Forward characteristics of reverse diode

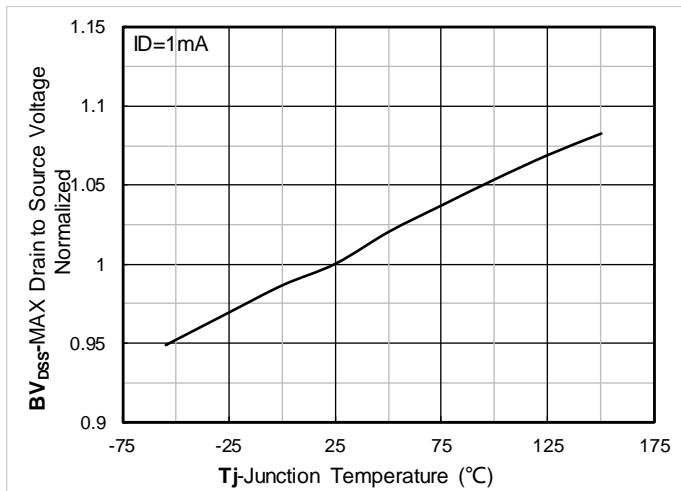


Figure 9. Normalized breakdown voltage

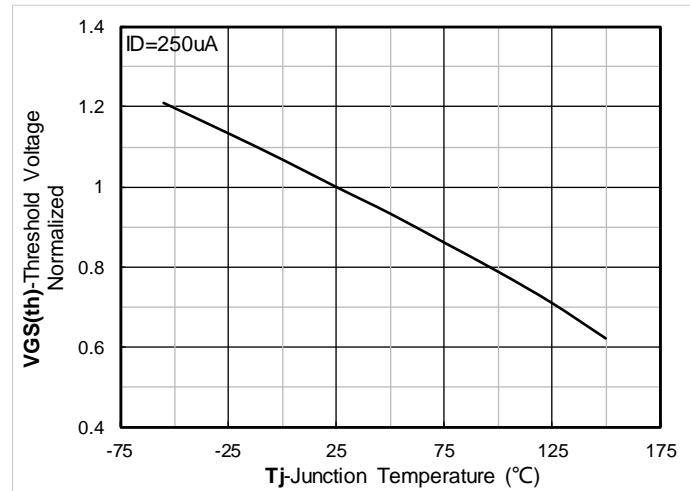


Figure 10. Normalized Threshold voltage

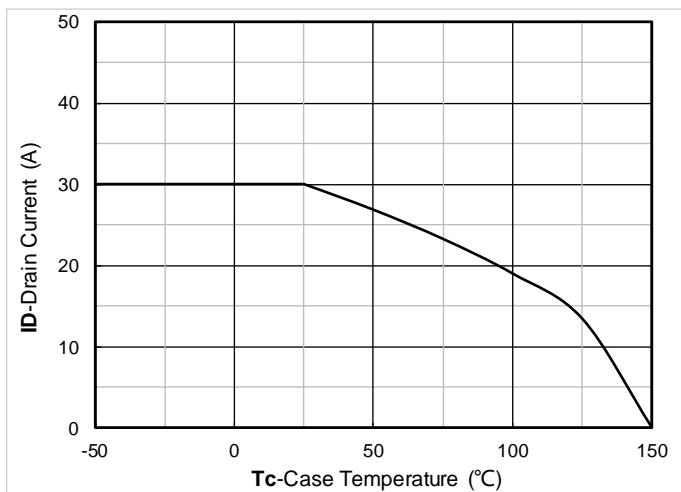


Figure 11. Current dissipation

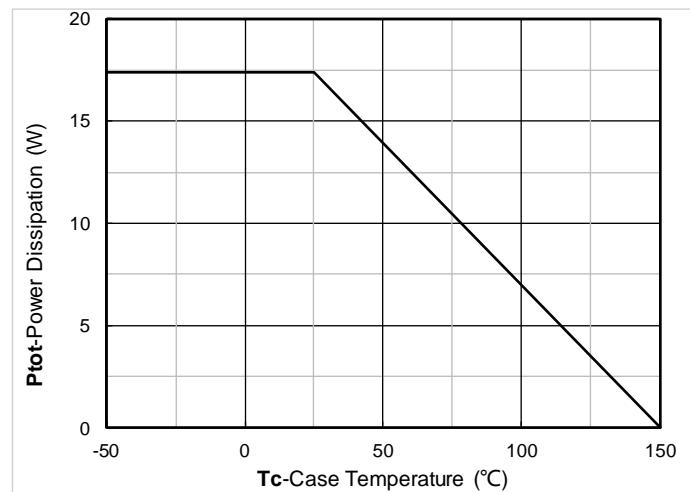


Figure 12. Power dissipation

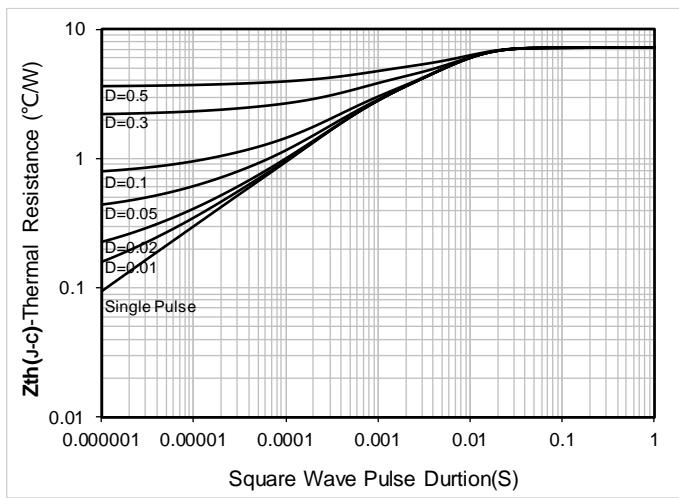


Figure 13. Maximum Transient Thermal Impedance

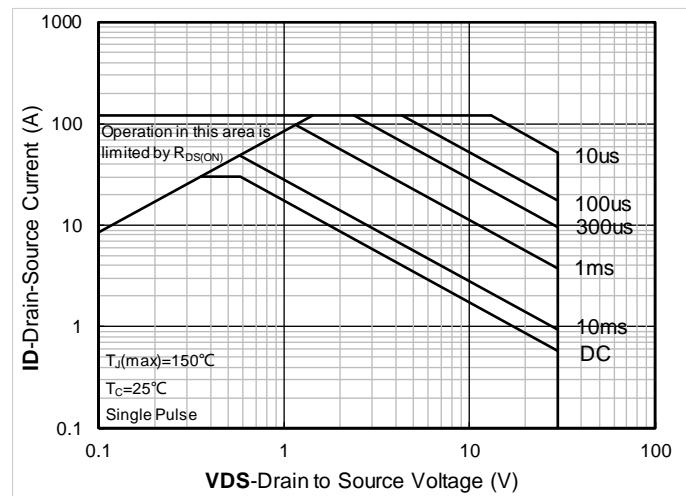


Figure 14. Safe Operation Area

■ NMOS(Die2) Typical Electrical and Thermal Characteristics Diagrams

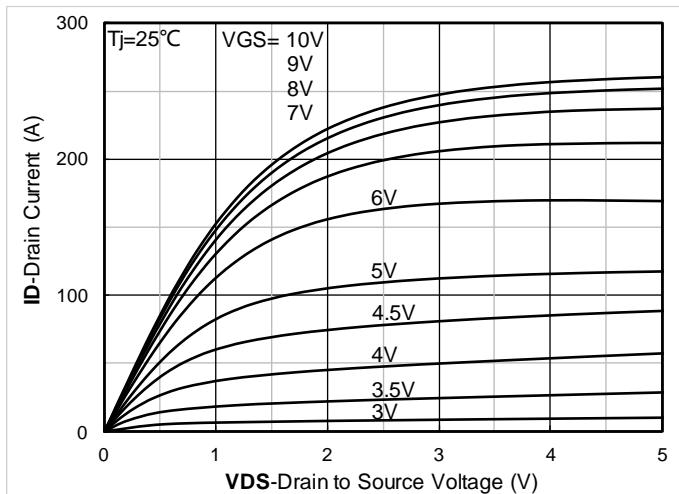


Figure 1. Output Characteristics

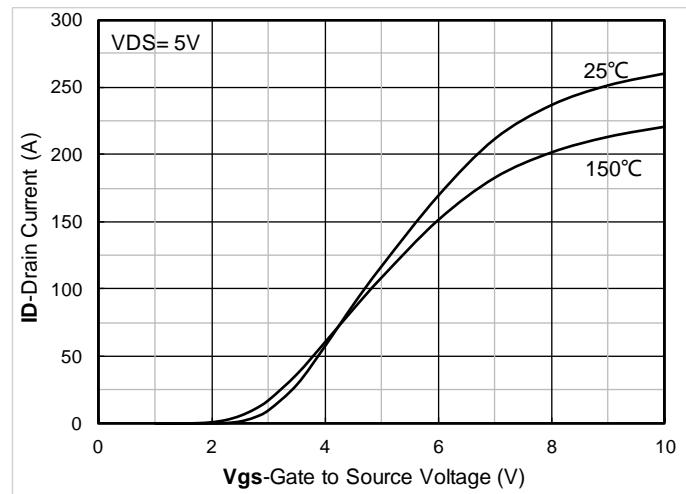


Figure 2. Transfer Characteristics

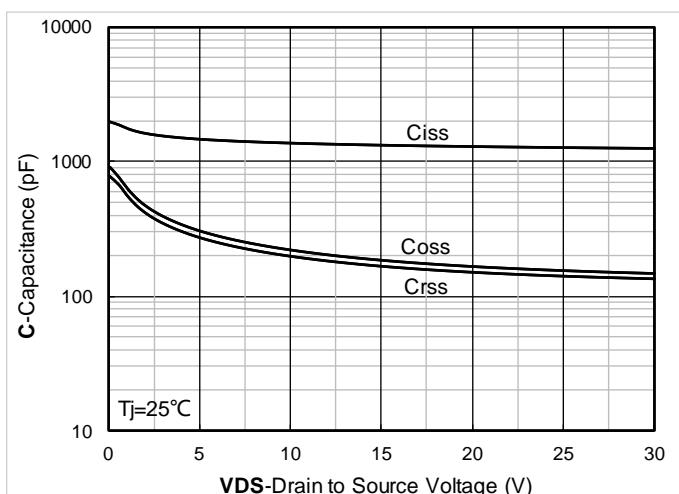


Figure 3. Capacitance Characteristics

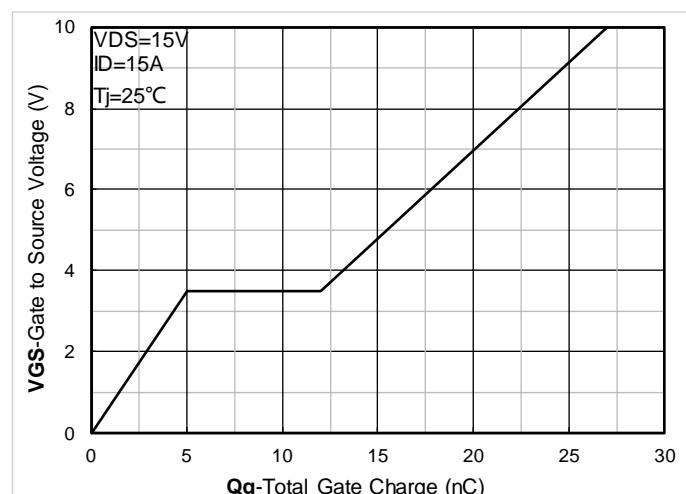


Figure 4. Gate Charge

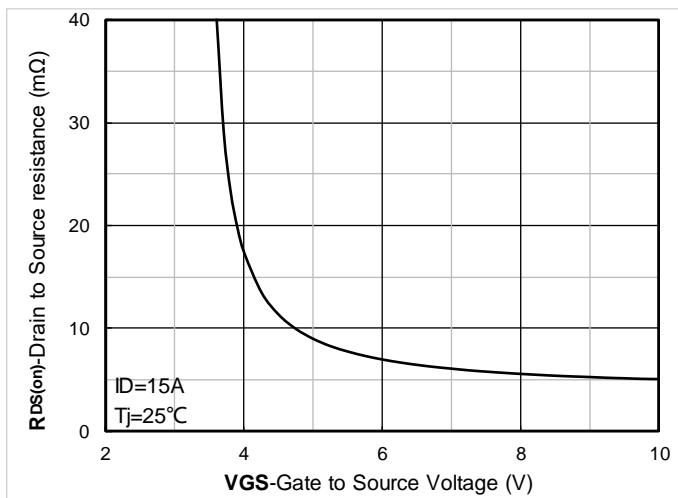


Figure 5. On-Resistance vs Gate to Source Voltage

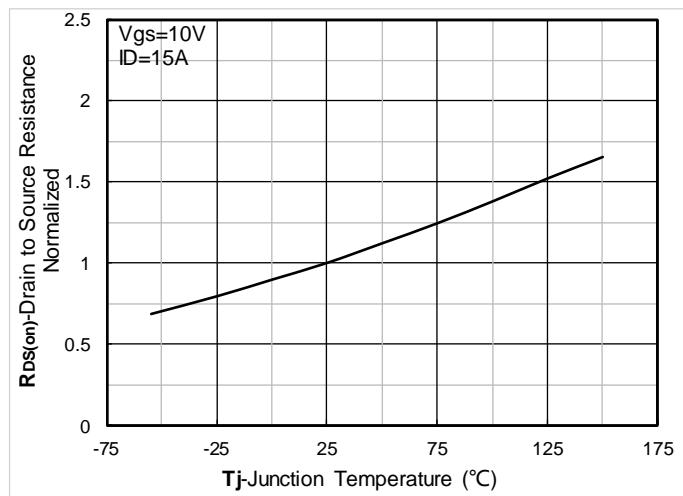


Figure 6. Normalized On-Resistance

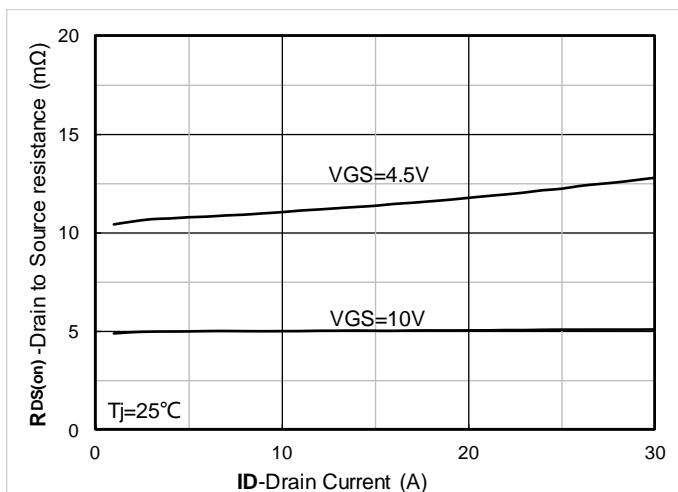


Figure 7. $R_{DS(on)}$ VS Drain Current

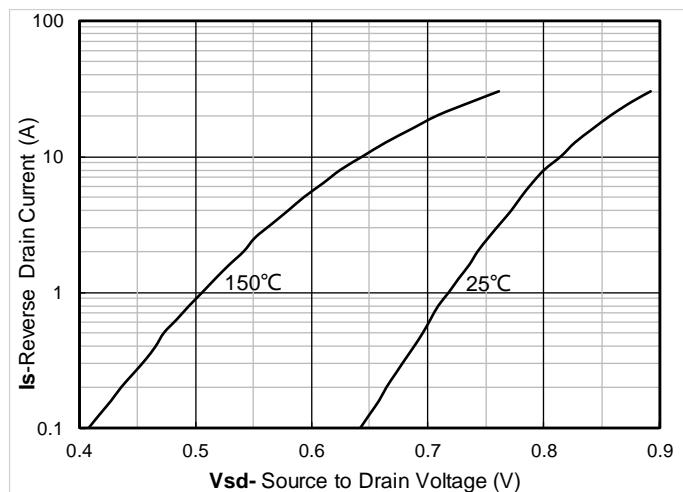


Figure 8. Forward characteristics of reverse diode

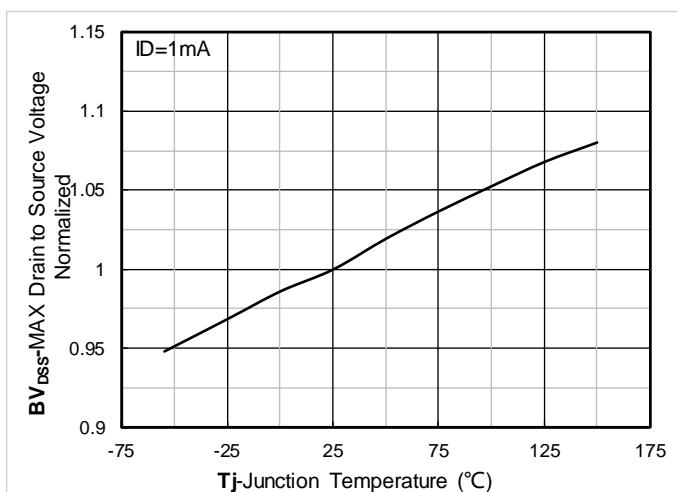


Figure 9. Normalized breakdown voltage

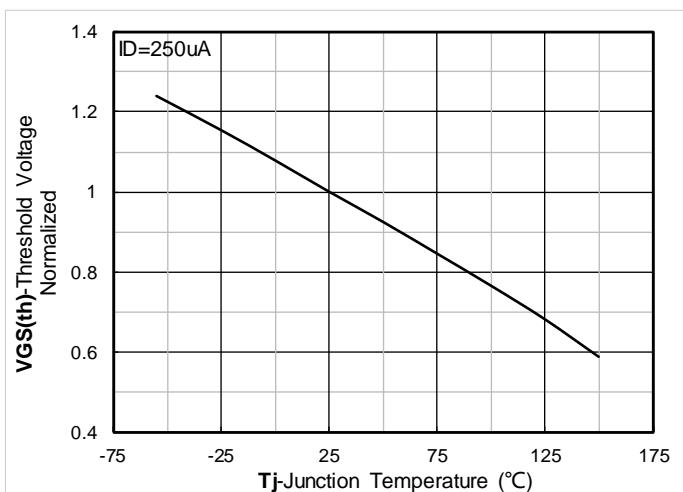


Figure 10. Normalized Threshold voltage

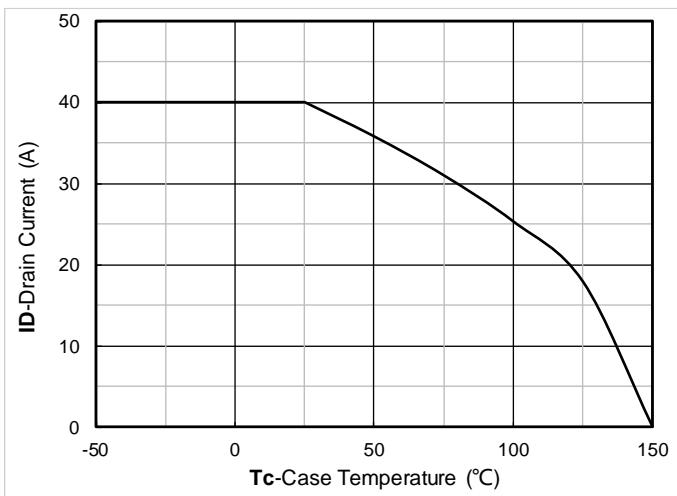


Figure 11. Current dissipation

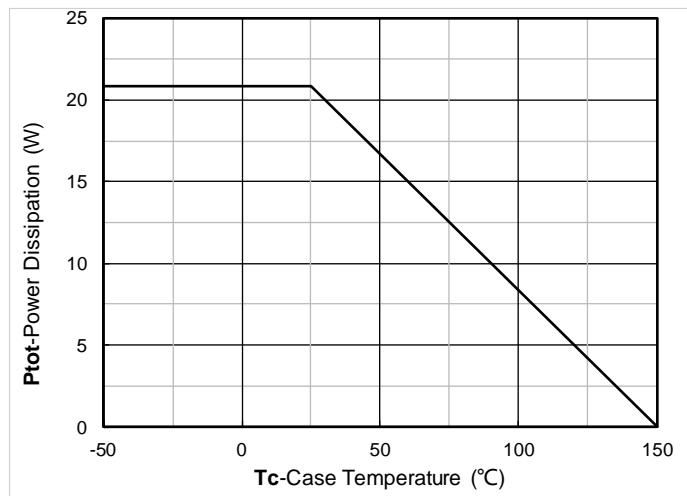


Figure 12. Power dissipation

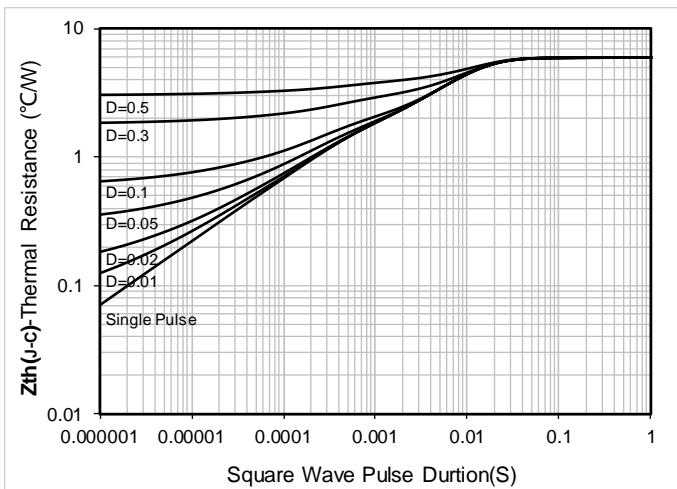


Figure 13. Maximum Transient Thermal Impedance

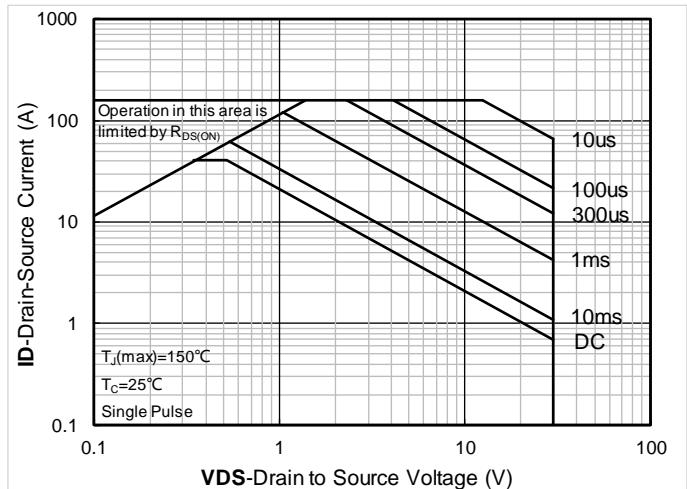
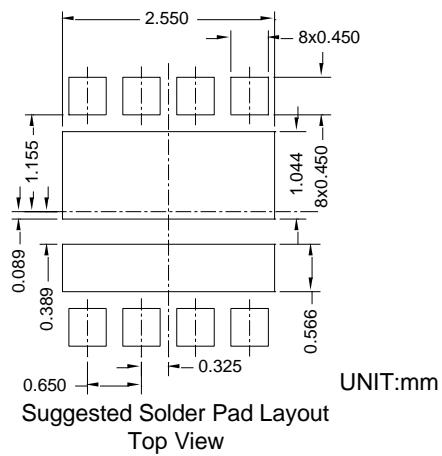
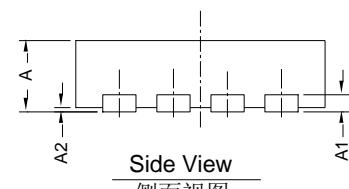
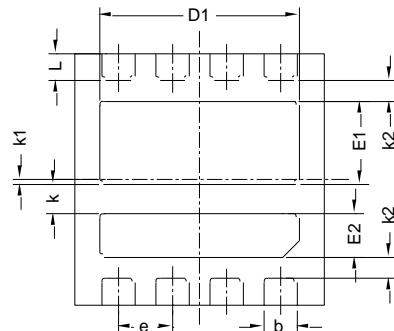
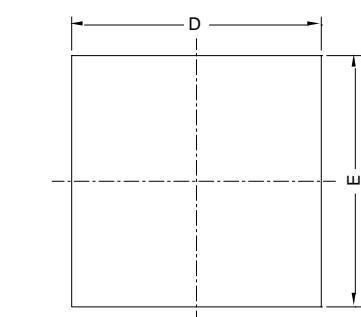


Figure 14. Safe Operation Area

■ DFN3030-8L Package information



SYMBOL	MILLIMETER		
	MIN	NOM	MAX
D	2.90	3.00	3.10
E	2.90	3.00	3.10
A	0.70	0.80	0.90
A1	0.20 BSC		
A2			0.10
D1	2.30	2.40	2.50
E1	0.89	0.99	1.09
E2	0.42	0.52	0.62
L	0.22	0.32	0.42
k	0.35 BSC		
k1	0.06 BSC		
k2	0.25 BSC		
b	0.30	0.40	0.50
e	0.65 BSC		

Note:

1. Controlling dimension:in millimeters.
2. General tolerance: $\pm 0.10\text{mm}$.
3. The pad layout is for reference purposes only.

Disclaimer

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The product listed herein is designed to be used with ordinary electronic equipment or devices, and not designed to be used with equipment or devices which require high level of reliability and the malfunction of which would directly endanger human life (such as medical instruments, transportation equipment, aerospace machinery, nuclear-reactor controllers, fuel controllers and other safety devices). Russiansunco or anyone on its behalf, assumes no responsibility or liability for any damages resulting from such improper use or sale.

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